Abstracts

The Influence of Pseudo-Random Numbers on Yield Analysis and Optimization of Microwave Circuits

Y. Huang and C. Sheng. "The Influence of Pseudo-Random Numbers on Yield Analysis and Optimization of Microwave Circuits." 1994 MTT-S International Microwave Symposium Digest 94.1 (1994 Vol. I [MWSYM]): 377-380.

In this paper, we analyze four sorts of Pseudo-Random Number (PRN) generators which are widely used in microwave circuit yield analysis and optimization, show that some PRN generators do not satisfy the requirements of simulating statistical models of circuit parameters, and reveal the influence of PRN statistical characteristic on yield analysis and optimization of microwave circuits. Finally, we give some suggestions worth of attention on establishing statistical models of microwave circuits and yield optimization.

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